MECHANICALLY VARIABLE TTL DELAY LINE (SERIES DDU37F)



FEATURES PACKAGES

• Ideal for "Set and Forget" applications

• Multi-turn adjustment screw (approx. 40 turns)

 Input & output fully TTL interfaced & buffered (10 T²L fan-out capability)

• **Resolution**: As low as 0.12ns

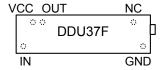
Minimum delay (T_{D0}): 6ns typical
 Output rise time: 2ns typical

Min. input pulse width: 20% of maximum delay
Power dissipation: 230mW maximum

Operating temperature: 0° to 70°C (Commercial)

-55° to 125°C (Military)

• Temperature coefficient: 100 PPM/°C



DDU37F-xx (Commercial)
DDU37F-xxM (Military)
xx = Dash number

FUNCTIONAL DESCRIPTION

The DDU37F-series device is a mechanically variable, FAST-TTL interfaced delay line. The signal input (IN) is reproduced at the tap output (OUT), shifted by an amount which can be adjusted between T_{D0} and $T_{D0} + T_{DVAR}$, where T_{DVAR} is given by the device dash number (See Table). The device operates from a single 5V supply and is TTL interfaced, capable of driving up to 10 TTL loads.

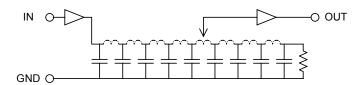
PIN DESCRIPTIONS

IN Signal Input OUT Fixed Output

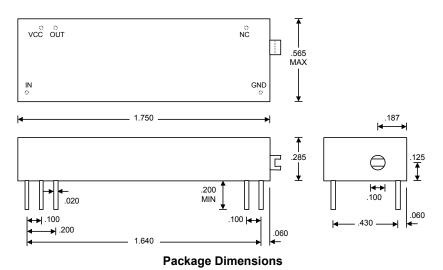
VCC +5V GND Ground

NC No connection

SERIES SPECIFICATIONS



Functional Diagram



DASH NUMBER SPECIFICATIONS

Part Number	T _{DVAR} (ns)
DDU37F-25	15
DDU37F-30	20
DDU37F-40	30
DDU37F-50	40
DDU37F-60	50
DDU37F-70	60
DDU37F-80	70
DDU37F-100	90
DDU37F-120	100
DDU37F-150	130
DDU37F-200	170

Note: Other delay times available on request

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APPLICATION NOTES

HIGH FREQUENCY RESPONSE

The DDU37F tolerances are guaranteed for input pulse widths and periods greater than those specified in the test conditions. Although the device will function properly for pulse widths as small as 20% of the total delay and periods as small as 40% of the total delay (for a symmetric input), the delays may deviate from their values at low frequency. However, for a given input condition, the deviation will be repeatable from pulse to pulse. Contact technical support at Data

Delay Devices if your application requires device testing at a specific input condition.

POWER SUPPLY BYPASSING

The DDU37F relies on a stable power supply to produce repeatable delays within the stated tolerances. A 0.1uf capacitor from VCC to GND, located as close as possible to the VCC pin, is recommended. A wide VCC trace and a clean ground plane should be used.

DEVICE SPECIFICATIONS

TABLE 1: ABSOLUTE MAXIMUM RATINGS

PARAMETER	SYMBOL	MIN	MAX	UNITS	NOTES
DC Supply Voltage	V _{CC}	-0.3	7.0	V	
Input Pin Voltage	V_{IN}	-0.3	V _{DD} +0.3	V	
Storage Temperature	T _{STRG}	-55	150	C	
Lead Temperature	T _{LEAD}		300	С	10 sec

TABLE 2: DC ELECTRICAL CHARACTERISTICS

(0C to 70C, 4.75V to 5.25V)

PARAMETER	SYMBOL	MIN	TYP	MAX	UNITS	NOTES
High Level Output Voltage	V_{OH}	2.5	3.4		V	$V_{CC} = MIN, I_{OH} = MAX$
						$V_{IH} = MIN, V_{IL} = MAX$
Low Level Output Voltage	V_{OL}		0.35	0.5	V	$V_{CC} = MIN, I_{OL} = MAX$
						$V_{IH} = MIN, V_{IL} = MAX$
High Level Output Current	I _{OH}			-1.0	mA	
Low Level Output Current	I _{OL}			20.0	mA	
High Level Input Voltage	V_{IH}	2.0			V	
Low Level Input Voltage	V_{IL}			8.0	V	
Input Clamp Voltage	V_{IK}			-1.2	V	$V_{CC} = MIN, I_I = I_{IK}$
Input Current at Maximum	I _{IHH}			0.1	mA	$V_{CC} = MAX, V_I = 7.0V$
Input Voltage						
High Level Input Current	I _{IH}			20	μΑ	$V_{CC} = MAX, V_I = 2.7V$
Low Level Input Current	I _{IL}			-0.6	mA	$V_{CC} = MAX, V_I = 0.5V$
Short-circuit Output Current	I _{os}	-60		-150	mA	V _{CC} = MAX
Output High Fan-out				25	Unit	
Output Low Fan-out				12.5	Load	

DELAY LINE AUTOMATED TESTING

TEST CONDITIONS

INPUT: **OUTPUT:**

Ambient Temperature: 25°C ± 3°C Load: 1 FAST-TTL Gate

Supply Voltage (Vcc): $5.0V \pm 0.1V$ 5pf ± 10% C_{load}:

Input Pulse: High = $3.0V \pm 0.1V$ Threshold: 1.5V (Rising & Falling)

Low = $0.0V \pm 0.1V$

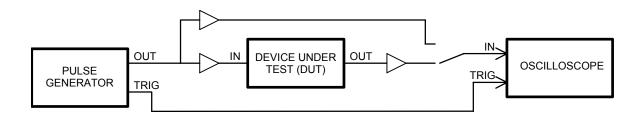
Source Impedance: 50Ω Max.

Rise/Fall Time: 3.0 ns Max. (measured

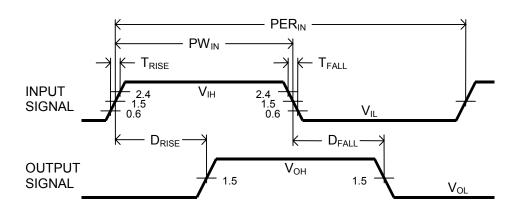
between 0.6V and 2.4V)

 $PW_{IN} = 1.5 \times Total Delay$ **Pulse Width:** Period: $PER_{IN} = 10 x Total Delay$

NOTE: The above conditions are for test only and do not in any way restrict the operation of the device.



Test Setup



Timing Diagram For Testing